

**NC-6800FLA FULLY-AUTO SHEET RESISTANCE/
RESISTIVITY MEASUREMENT & SORTING SYSTEM**

NC-6800FLA



- Fully automatic sheet resistance / resistivity measurement with belt transfer sorting system
- Multi-point, Non-Contact Type using Eddy current method
- Resistivity, thickness and conductivity (P/N) measurements
- Number of cassette station can be customized on request
- Electrical capacitance method for wafer thickness
- Temperature correction for silicon wafer function
- Thickness measure range: 150um to 800um
- Measure Range depends on selected Probe type
- Sample Size (∅): 3" to 8"

MEASURE RANGE

PARAMETER	LOW PROBE TYPE	MIDDLE PROBE TYPE	HIGH PROBE TYPE	S-HIGH PROBE TYPE
RESISTIVITY (Ω.cm)	0.001 to 0.05	0.05 to 0.5	0.5 to 60.0	60.0 to 200.0
SHEET RESISTANCE (Ω/Sq)	0.01 to 0.5	0.5 to 10.0	10.0 to 1k	1k to 3k

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)

